




<p>Searched</p> 	<p>Application/Control No.</p> <p>10811403</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>CHEN ET AL.</p>
	<p>Examiner</p> <p>Tran, Mai T</p>	<p>Art Unit</p> <p>2129</p>

Class	SubClass	Date	Examiner
--------------	-----------------	-------------	-----------------

U.S. Patent and Trademark Office	Part of Paper No.: 09202006
----------------------------------	-----------------------------

Search Notes 	Application/Control No. 10811403	Applicant(s)/Patent Under Reexamination CHEN ET AL.
	Examiner Tran, Mai T	Art Unit 2129

Notes	Date	Examiner
EAST (Please see search history printout)	9/22/2006	mtt
ACM Portal (Please see search history printout)	9/22/2006	mtt
Google (Please see search history printout)	9/22/2006	mtt
IEEE (Please see search history printout)	9/22/2006	mtt
Plus Search (Please see search results scanned in eDAN)	9/20/2006	mtt
U.S. Patent and Trademark Office		Part of Paper No.: 09202006

Interference Searched 	Application/Control No. 10811403	Applicant(s)/Patent Under Reexamination CHEN ET AL.
	Examiner Tran, Mai T	Art Unit 2129

Class	SubClass	Date	Examiner
-------	----------	------	----------

U.S. Patent and Trademark Office	Part of Paper No.: 09202006
----------------------------------	-----------------------------